

ABSTRACT

There are included a mother board (11), which has therein a multiplexer and a test pass/fail determining part, and a daughter board (12) that has therein an A/D converting part and an averaging part. The mother board (11) multiplexes a plurality of analog signals outputted from a plurality of output terminals of an LSI formed on a wafer (W) to be tested, thereby reducing the number of signals in an early stage. The daughter board (12) A/D converts and averages the resultant signals from the mother board (11), and supplies the averaged characteristic measured data to the mother board (11) for a pass/fail determination. This can eliminate the need for a large number of parallel transmission paths and processing circuits, raise the throughput, and reduce the affections of noise included in the analog signals due to the average processing.